



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

José Carlos ORTIZ ALEMÁN et al.

Serial No.: 10/568,814

Filed: September 6, 2006

For: METHOD FOR IMAGING MULTI-

PHASE FLOW USING ELECTRICAL CAPACITANCE TOMOGRAPHY

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with 37 C.F.R. § 1.97 and § 1.98, Applicants bring the disclosures listed on attached Form PTO-1449 to the Examiner's attention and request that they be considered and made of record in the subject application.

Prompt examination on the merits is respectfully requested.

Respectfully submitted,

Garrett V. Davis Reg. No. 32,023

Roylance, Abrams, Berdo & Goodman, L.L.P. 1300 19th Street, N.W., Suite 600 Washington, D.C. 20036 (202) 659-9076

Dated: Jag 19200 >



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	Application Number		10568814	
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INFORMATION DISCLOSURE	First Named Inventor Jose C		Carlos Ortiz Aleman	
STATEMENT BY APPLICANT (Not for submission under 37 CFR 1.99)	Art Unit			
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